

**CLAIM AMENDMENTS**

**IN THE CLAIMS**

This listing of the claims will replace all prior versions, and listing, of claims in the application or previous response to office action:

1.     **(Cancelled)** A system for testing a display device, comprising:
  - (a)     a base comprising a first surface, the first surface defining at least four apertures; and
  - (b)     the display device comprising a first surface, a first layer, and a second layer, the first layer comprising a semiconductor substrate, the second layer comprising a transparent material;  
  
          wherein the first surface of the display device is coupled to the first surface of the base at each of the at least four apertures such that gravitational forces on the display device are optimally counterbalanced.
2.     **(Amended)** The system of claim 47 1, wherein the base is a vacuum box.
3.     **(Original)** The system of claim 2, wherein the display device is coupled to the first surface of the vacuum box at each of the at least four apertures by the pressure differential between the atmosphere and the interior of the vacuum box.
4.     **(Amended)** The system of claim 47 1, wherein the semiconductor substrate is silicon.
5.     **(Amended)** The system of claim 47 1, wherein the transparent material is glass.
6.     **(Amended)** The system of claim 47 1, wherein the first surface of the display device is closer to the first layer than the second layer.
7.     **(Amended)** The system of claim 47 1, wherein **a surface of the first layer forms** the first surface of the display device ~~is a surface of the first layer~~.

8. (Amended) The system of claim 47 1, wherein four of the at least four apertures are arranged at the vertices of a rectangle.
9. (Amended) The system of claim 47 1, wherein four of the at least four apertures are arranged in two pairs with the distance between the apertures in a pair being less than a fifth the distance between the pairs.
10. (Amended) The system of claim 47 1, wherein the first surface of the base defines a second plurality of apertures at which the display device is not coupled.
11. (Cancelled) A system for testing a display device, comprising:  
(a) a vacuum box comprising a first surface; and  
(b) the display device comprising a first layer and a second layer, the first layer comprising a silicon substrate, the second layer comprising a transparent material; and  
wherein the first layer of the display device is coupled to the first surface of the vacuum box.
12. (Amended) The system of claim 48 1, wherein the vacuum box is mounted on a rotating base.
13. (Amended) The system of claim 48 1, wherein the vacuum box comprises a cover having the first surface and a vacuum block.
14. (Amended) The system of claim 48 1, wherein the display device is a micro display.
15. (Amended) The system of claim 48 1, wherein the first surface of the vacuum box defines at least two apertures and the first layer of the display device is coupled to the first surface of the vacuum box at the at least two apertures.
16. (Original) The system of claim 15, wherein the first layer of the display device is coupled to the first surface of the vacuum box at the at least two apertures by a pressure differential.

17. **(Amended)** The system of claim 48 1, wherein the vacuum box is mounted on a first base that is movably engaged along a first axis to a second base.

18. **(Original)** The system of claim 17, wherein the second base is movably engaged along a second axis to a third base and the second axis is perpendicular to the first axis.

19.-46. **(Cancelled)**.

47. **(Newly Added)** A system for testing a display device, the display device having a first surface, a first layer formed of semiconductor substrate and a second layer formed of a transparent material, the system comprising:

- a base having a first surface;
- a first plurality of at least four apertures formed in the first surface of the base; and
- the at least four apertures operable to couple the first surface of the display device to the first surface of the base and further operable to optimally counterbalance gravitational forces on the display device in maintaining the coupling between the display device and the base during display device testing.

48. **(Newly Added)** A system for testing a display device, the display device having a first surface, a first layer formed of semiconductor substrate and a second layer formed of a transparent material, the system comprising:

- a vacuum box including a first surface; and
- the first surface operable to couple the first layer of the display device to the vacuum box and further operable to maintain the display device substantially free from distorting forces in a predetermined position relative a testing apparatus during testing.

49. **(Newly Added)** A system for testing a display device, the display device having a first surface, a first layer formed of semiconductor substrate and a second layer formed of a transparent material, the system comprising:

- a vacuum box;
- a cover operably coupled to the vacuum box;
- a plurality of apertures disposed proximate a first side of the cover, the apertures arranged in a substantially rectangular pattern; and
- the plurality of apertures operable to couple the display device to the vacuum box during testing such that the display device is maintained in a predetermined position relative a display device testing apparatus substantially free from tensile forces.